CY74FCT652T 8-BIT REGISTERED TRANSCEIVER WITH 3-STATE OUTPUTS

SCCS032B - SEPTEMBER 1994 - REVISED OCTOBER 2001

- **Function, Pinout, and Drive Compatible** With FCT and F Logic
- Reduced V_{OH} (Typically = 3.3 V) Version of **Equivalent FCT Functions**
- **Edge-Rate Control Circuitry for** Significantly Improved Noise Characteristics
- Ioff Supports Partial-Power-Down Mode Operation
- **Matched Rise and Fall Times**
- Fully Compatible With TTL Input and **Output Logic Levels**
- 64-mA Output Sink Current 32-mA Output Source Current
- Independent Register for A and B Buses
- **Multiplexed Real-Time and Stored Data Transfer**
- **3-State Outputs**

(TOP VIEW) CPAB [24 🛮 V_{CC} SAB [] 2 23 CPBA GAB [] 3 22 T SBA 21 GBA $A_1 \prod 4$ 20 B₁ A₂ [] 5 19 B₂ A₃ 🛮 6 Α₄Γ 18∏ B₃ A₅ 🛮 8 17 🛮 B₄ A₆ 🛮 9 16 B₅ 15 B₆ A₇ 🛮 10 14 🛮 B₇ A₈ 📙 11 GND **1**12 13 B₈

Q OR SO PACKAGE

description

The CY74FCT652T consists of bus transceiver circuits, D-type flip-flops, and control circuitry arranged for multiplexed transmission of data directly from the input bus or from the internal storage registers. GAB and GBA inputs control the transceiver functions. Select-control (SAB and SBA) inputs select either real-time or stored-data transfer. The circuitry used for select control eliminates the typical decoding glitch that occurs in a multiplexer during the transition between stored and real-time data. A low input level selects real-time data, and a high input level selects stored data.

Data on the A or B data bus, or both, can be stored in the internal D-type flip-flops by low-to-high transitions of the appropriate clock (CPAB or CPBA) inputs, regardless of the select or enable levels of the control pins. When SAB and SBA are in the real-time transfer mode, it also is possible to store data without using the internal D-type flip-flops by simultaneously enabling GAB and GBA. In this configuration, each output reinforces its input. Thus, when all other data sources to the two sets of bus lines are at high impedance, each set of bus lines remains at its last state.

This device is fully specified for partial-power-down applications using Ioff. The Ioff circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



testing of all parameters

Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



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ORDERING INFORMATION

| TA | PACKAGE [†] | | PACKAGE [†] | | SPEED ORDERABLE (ns) PART NUMBER | | TOP-SIDE MARKING |
|---------------|----------------------|---------------|----------------------|------------------|----------------------------------|--|---------------------|
| | QSOP – Q | Tape and reel | 5.4 | CY74FCT652CTQCT | FCT652C | | |
| | SOIC - SO | Tube | 5.4 | CY74FCT652CTSOC | FCT652C | | |
| | SOIC = SO | Tape and reel | 5.4 | CY74FCT652CTSOCT | FC1052C | | |
| –40°C to 85°C | QSOP - Q | Tape and reel | 6.3 | CY74FCT652ATQCT | FCT652A | | |
| | SOIC - SO | Tube | 6.3 | CY74FCT652ATSOC | FCT652A | | |
| | 3010 - 30 | Tape and reel | 6.3 | CY74FCT652ATSOCT | FC1002A | | |
| | QSOP - Q | Tape and reel | 9 | CY74FCT652TQCT | FCT652 | | |

[†] Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

FUNCTION TABLE

| | 1 3 1 3 1 3 1 3 1 3 1 3 1 3 1 3 1 3 1 3 | | | | | | | | | | |
|-----|---|------------|------------|----------------|-----|--------------------------------|--------------------------------|--|--|--|--|
| | | INP | UTS | | | DAT | A I/O | OPERATION OR | | | |
| GAB | GBA | CPAB | СРВА | SAB | SBA | A ₁ -A ₈ | B ₁ -B ₈ | FUNCTION | | | |
| L | Н | H or L | H or L | Χ | Х | Input | Input | Isolation | | | |
| L | Н | \uparrow | 1 | Χ | Χ | Input | Input | Store A and B data | | | |
| Х | Н | 1 | H or L | Х | Х | Input | Unspecified§ | Store A, hold B | | | |
| Н | Н | \uparrow | \uparrow | X [‡] | Χ | Input | Output | Store A in both registers | | | |
| L | Х | H or L | 1 | Χ | Х | Unspecified§ | Input | Hold A, store B | | | |
| L | L | \uparrow | 1 | Χ | χ‡ | Output | Input | Store B in both registers | | | |
| L | L | Х | Χ | Χ | L | Output | Input | Real-time B data to A bus | | | |
| L | L | Χ | H or L | Χ | Н | Output | Input | Stored B data to A bus | | | |
| Н | Н | Х | Х | L | Х | Input | Output | Real-time A data to B bus | | | |
| Н | Н | H or L | Χ | Н | Χ | Input | Output | Stored A data to B bus | | | |
| Н | L | H or L | H or L | Н | Н | Output | Output | Stored A data to B bus and Stored B data to A bus | | | |

 $H = High logic level, L = Low logic level, X = Don't care, \uparrow = Low-to-high transition$



[‡] Select control = L: clocks can occur simultaneously. Select control = H: clocks must be staggered in order to load both registers.

[§] The data output functions can be enabled or disabled by various signals at the GAB and GBA inputs. Data input functions always are enabled, i.e., data at the bus pins are stored on every low-to-high transition of the clock inputs.

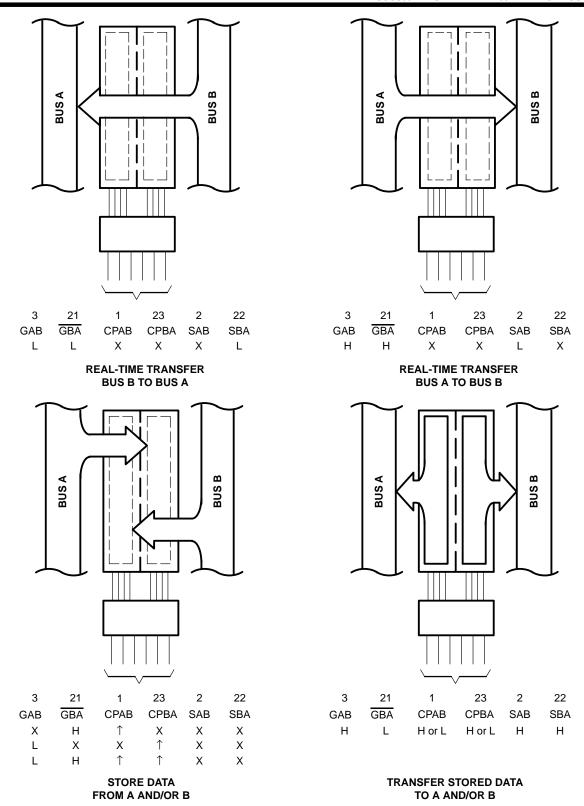
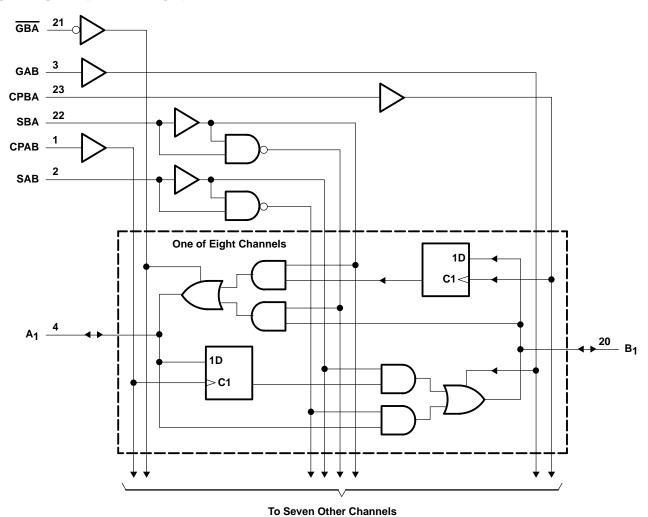


Figure 1. Bus-Management Functions



logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

| Supply voltage range to ground potential | | 0.5 | \mbox{V} to 7 \mbox{V} |
|---|-------------------|-------------------|----------------------------|
| DC input voltage range | | 0.5 | \mbox{V} to 7 \mbox{V} |
| DC output voltage range | | 0.5 | \mbox{V} to 7 \mbox{V} |
| DC output current (maximum sink current/pin) | | | 120 mA |
| Package thermal impedance, θ _{JA} (see Note 1) |): Q package | | 61°C/W |
| | SO package | | 46°C/W |
| Ambient temperature range with power applied | d, T _A | . <i>–</i> 65°C t | to 135°C |
| Storage temperature range, T _{stq} | | . −65°C t | to 150°C |

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 2)

| | | MIN | NOM | MAX | UNIT |
|-----------------|--------------------------------|------|-----|------|------|
| Vcc | Supply voltage | 4.75 | 5 | 5.25 | V |
| VIH | High-level input voltage | 2 | | | V |
| VIL | Low-level input voltage | | | 0.8 | V |
| IOH | High-level output current | | | -32 | mA |
| l _{OL} | Low-level output current | | | 64 | mA |
| TA | Operating free-air temperature | -40 | | 85 | °C |

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation.



NOTES: 1. The package thermal impedance is calculated in accordance with JESD 51-7.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | 3 | MIN | TYP [†] | MAX | UNIT |
|-------------------------------|--|---|--|-----|------------------|------|------------|
| VIK | $V_{CC} = 4.75 \text{ V},$ | I _{IN} = -18 mA | | | -0.7 | -1.2 | V |
| V | V 4.75.V | I _{OH} = -32 mA | | 2 | | | V |
| VOH | V _{CC} = 4.75 V | I _{OH} = -15 mA | | 2.4 | 3.3 | | V |
| VoL | $V_{CC} = 4.75 \text{ V},$ | I _{OL} = 64 mA | | | 0.3 | 0.55 | V |
| V_{hys} | All inputs | | | | 0.2 | | V |
| lį | $V_{CC} = 5.25 \text{ V},$ | $V_{IN} = V_{CC}$ | | | | 5 | μΑ |
| lін | $V_{CC} = 5.25 \text{ V},$ | V _{IN} = 2.7 V | | | | ±1 | μΑ |
| I _Ι Γ | $V_{CC} = 5.25 \text{ V},$ | V _{IN} = 0.5 V | | | | ±1 | μΑ |
| lozн | V _{CC} = 5.25 V, | V _{OUT} = 2.7 V | | | - | 10 | μΑ |
| lozl | $V_{CC} = 5.25 \text{ V},$ | V _{OUT} = 0.5 V | | | | -10 | μΑ |
| los [‡] | $V_{CC} = 5.25 \text{ V},$ | V _{OUT} = 0 V | | -60 | -120 | -225 | mA |
| l _{off} | $V_{CC} = 0 V$, | V _{OUT} = 4.5 V | | | | ±1 | μΑ |
| lcc | $V_{CC} = 5.25 \text{ V},$ | $V_{IN} \le 0.2 V$, | $V_{IN} \ge V_{CC} - 0.2 V$ | | 0.1 | 0.2 | mA |
| ∆lCC | $V_{CC} = 5.25 \text{ V}, V_{IN} = 3$ | .4 V , $f_1 = 0$, Outputs ope | en | | 0.5 | 2 | mA |
| ^I CCD [¶] | | out switching at 50% duty $I_{N} \le 0.2 \text{ V or } V_{IN} \ge V_{CC}$ | | | 0.06 | 0.12 | mA/ MHz |
| | $V_{CC} = 5.25 \text{ V},$ $f_0 = 10 \text{ MHz},$ | One bit switching at f ₁ = 5 MHz | $V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$ | | 0.7 | 1.4 | |
| l _C # | Outputs open, | at 50% duty cycle | $V_{IN} = 3.4 \text{ V or GND}$ | | 1.2 | 3.4 | mA |
| IC" | $GAB = \overline{GBA} = GND,$ SAB = CPAB = GND, | Eight bits switching at f ₁ = 5 MHz | $V_{IN} \le 0.2 \text{ V or}$ $V_{IN} \ge V_{CC} - 0.2 \text{ V}$ | | 2.8 | 5.6 | IIIA |
| | SBA = V _{CC} | at 50% duty cycle | V _{IN} = 3.4 V or GND | | 5.1 | 14.6 | |
| Ci | | | | | 5 | 10 | pF |
| Co | | | | | 9 | 12 | pF |

[†] Typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

I_C = I_{CC} + Δ I_{CC} × D_H × N_T + I_{CCD} (f₀/2 + f₁ × N₁) Where:

IC = Total supply current

I_{CC} = Power-supply current with CMOS input levels

 ΔI_{CC} = Power-supply current for a TTL high input ($V_{IN} = 3.4 \text{ V}$)

D_H = Duty cycle for TTL inputs high N_T = Number of TTL inputs at D_H

I_{CCD} = Dynamic current caused by an input transition pair (HLH or LHL)

f₀ = Clock frequency for registered devices, otherwise zero

f₁ = Input signal frequency

N₁ = Number of inputs changing at f₁

All currents are in milliamperes and all frequencies are in megahertz.

Values for these conditions are examples of the I_{CC} formula.



^{*} Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high-speed test apparatus and/or sample-and-hold techniques are preferable to minimize internal chip heating and more accurately reflect operational values. Otherwise, prolonged shorting of a high output can raise the chip temperature well above normal and cause invalid readings in other parametric tests. In any sequence of parameter tests, IOS tests should be performed last.

 $[\]$ Per TTL-driven input ($V_{IN} = 3.4 \text{ V}$); all other inputs at V_{CC} or GND

 $[\]P$ This parameter is derived for use in total power-supply calculations.

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timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 2)

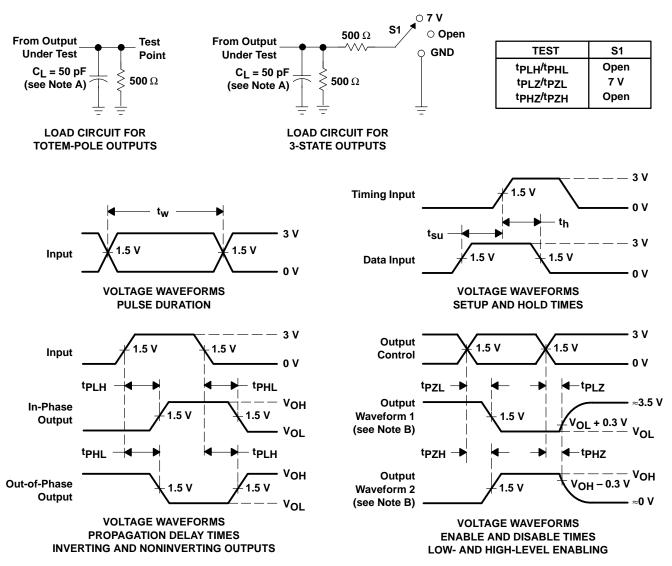
| | _(| | | | CY74FCT652AT | | CY74FCT652CT | | UNIT |
|-----------------|-----------------------------------|--------|-----|-----|--------------|-----|--------------|-----|------|
| | | | MIN | MAX | MIN | MAX | MIN | MAX | UNIT |
| t _W | Pulse duration, clock high or low | | 6 | | 5 | | 5 | | ns |
| t _{su} | Setup time, before CPAB↑ or CPBA↑ | A or B | 4 | | 2 | | 2 | | ns |
| th | Hold time, after CPAB↑ or CPBA↑ | A or B | 2 | | 1.5 | | 1.5 | | ns |

switching characteristics over operating free-air temperature range (see Figure 2)

| PARAMETER | FROM | TO (OUTPUT) | CY74FC | CT652T | CY74FC | Γ652AT | CY74FCT652CT | | UNIT |
|------------------|--------------|----------------|--------|--------|--------|--------|--------------|-----|------|
| PARAMETER | (INPUT) | | MIN | MAX | MIN | MAX | MIN | MAX | UNII |
| t _{PLH} | A or B | B or A | 1.5 | 9 | 1.5 | 6.3 | 1.5 | 5.4 | ns |
| t _{PHL} | AUIB | BULA | 1.5 | 9 | 1.5 | 6.3 | 1.5 | 5.4 | 110 |
| ^t PZH | GAB or GBA | A or B | 1.5 | 14 | 1.5 | 9.8 | 1.5 | 7.8 | ns |
| t _{PZL} | GAB OI GBA | AUIB | 1.5 | 14 | 1.5 | 9.8 | 1.5 | 7.8 | 115 |
| ^t PHZ | GAB or GBA | A or B | 1.5 | 9 | 1.5 | 6.3 | 1.5 | 6.3 | ns |
| ^t PLZ | GAB OI GBA | | 1.5 | 9 | 1.5 | 6.3 | 1.5 | 6.3 | 115 |
| t _{PLH} | CPAB or CPBA | A or B | 1.5 | 9 | 1.5 | 6.3 | 1.5 | 5.7 | ns |
| ^t PHL | CFAB OI CFBA | AUB | 1.5 | 9 | 1.5 | 6.3 | 1.5 | 5.7 | 110 |
| tPLH | SBA or SAB | A - : D | 1.5 | 11 | 1.5 | 7.7 | 1.5 | 6.2 | |
| ^t PHL | SBA UI SAB | A or B | 1.5 | 11 | 1.5 | 7.7 | 1.5 | 6.2 | ns |



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 2. Load Circuit and Voltage Waveforms









PACKAGING INFORMATION

| Orderable Device | Status (1) | Package Type | Package Drawing | Pins | Package Qty | e Eco Plan ⁽²⁾ | Lead/Ball Finish | MSL Peak Temp ⁽³⁾ |
|--------------------|------------|-----------------|--------------------|------|----------------|---------------------------|------------------|------------------------------|
| CY74FCT652ATQCT | ACTIVE | SSOP/ QSOP | DBQ | 24 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR |
| CY74FCT652ATQCTE4 | ACTIVE | SSOP/ QSOP | DBQ | 24 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR |
| CY74FCT652ATQCTG4 | ACTIVE | SSOP/ QSOP | DBQ | 24 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR |
| CY74FCT652ATSOC | ACTIVE | SOIC | DW | 24 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652ATSOCE4 | ACTIVE | SOIC | DW | 24 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652ATSOCG4 | ACTIVE | SOIC | DW | 24 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652ATSOCT | ACTIVE | SOIC | DW | 24 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652ATSOCTE4 | ACTIVE | SOIC | DW | 24 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652ATSOCTG4 | ACTIVE | SOIC | DW | 24 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652CTQCT | ACTIVE | SSOP/ QSOP | DBQ | 24 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR |
| CY74FCT652CTQCTE4 | ACTIVE | SSOP/ QSOP | DBQ | 24 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR |
| CY74FCT652CTQCTG4 | ACTIVE | SSOP/ QSOP | DBQ | 24 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR |
| CY74FCT652CTSOC | ACTIVE | SOIC | DW | 24 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652CTSOCE4 | ACTIVE | SOIC | DW | 24 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652CTSOCG4 | ACTIVE | SOIC | DW | 24 | 25 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652CTSOCT | ACTIVE | SOIC | DW | 24 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652CTSOCTE4 | ACTIVE | SOIC | DW | 24 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652CTSOCTG4 | ACTIVE | SOIC | DW | 24 | 2000 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-1-260C-UNLIM |
| CY74FCT652TQCT | ACTIVE | SSOP/ QSOP | DBQ | 24 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR |
| CY74FCT652TQCTE4 | ACTIVE | SSOP/ QSOP | DBQ | 24 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR |
| CY74FCT652TQCTG4 | ACTIVE | SSOP/ QSOP | DBQ | 24 | 2500 | Green (RoHS & no Sb/Br) | CU NIPDAU | Level-2-260C-1 YEAR |

 $^{^{(1)}}$ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.



PACKAGE OPTION ADDENDUM

24-May-2007

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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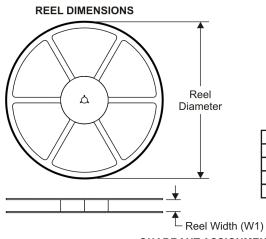
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

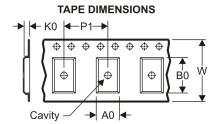




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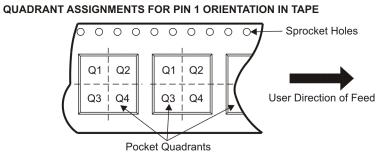
TAPE AND REEL INFORMATION





| | Dimension designed to accommodate the component width |
|----|---|
| | Dimension designed to accommodate the component length |
| | Dimension designed to accommodate the component thickness |
| W | Overall width of the carrier tape |
| P1 | Pitch between successive cavity centers |

- Reel Width (W1)

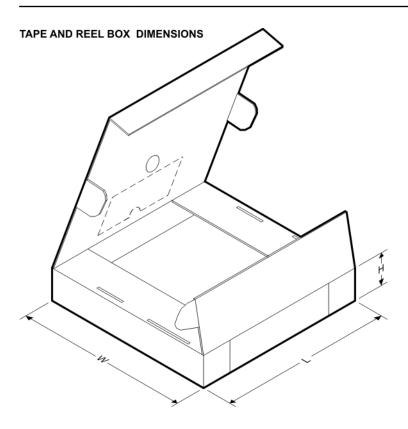


*All dimensions are nominal

| Device | Package Type | Package Drawing | | SPQ | Reel Diameter (mm) | Reel Width W1 (mm) | A0 (mm) | B0 (mm) | K0 (mm) | P1 (mm) | W (mm) | Pin1 Quadrant |
|------------------|-----------------|--------------------|----|------|--------------------------|--------------------------|---------|---------|---------|------------|-----------|------------------|
| CY74FCT652ATQCT | SSOP/ QSOP | DBQ | 24 | 2500 | 330.0 | 16.4 | 6.5 | 9.0 | 2.1 | 8.0 | 16.0 | Q1 |
| CY74FCT652ATSOCT | SOIC | DW | 24 | 2000 | 330.0 | 24.4 | 10.75 | 15.7 | 2.7 | 12.0 | 24.0 | Q1 |
| CY74FCT652CTQCT | SSOP/ QSOP | DBQ | 24 | 2500 | 330.0 | 16.4 | 6.5 | 9.0 | 2.1 | 8.0 | 16.0 | Q1 |
| CY74FCT652CTSOCT | SOIC | DW | 24 | 2000 | 330.0 | 24.4 | 10.75 | 15.7 | 2.7 | 12.0 | 24.0 | Q1 |
| CY74FCT652TQCT | SSOP/ QSOP | DBQ | 24 | 2500 | 330.0 | 16.4 | 6.5 | 9.0 | 2.1 | 8.0 | 16.0 | Q1 |

PACKAGE MATERIALS INFORMATION

11-Mar-2008

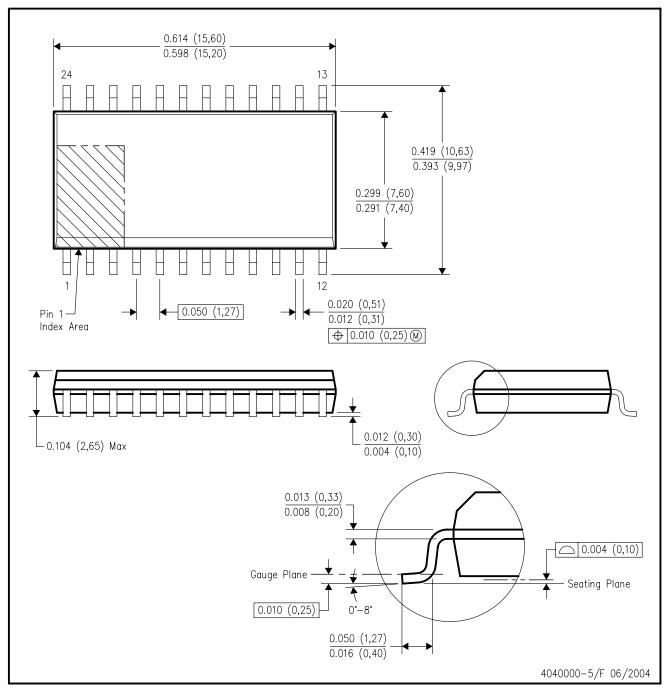


*All dimensions are nominal

| 7 til dilliciolorio are nominal | | | | | | | |
|---------------------------------|--------------|-----------------|------|------|-------------|------------|-------------|
| Device | Package Type | Package Drawing | Pins | SPQ | Length (mm) | Width (mm) | Height (mm) |
| CY74FCT652ATQCT | SSOP/QSOP | DBQ | 24 | 2500 | 346.0 | 346.0 | 33.0 |
| CY74FCT652ATSOCT | SOIC | DW | 24 | 2000 | 346.0 | 346.0 | 41.0 |
| CY74FCT652CTQCT | SSOP/QSOP | DBQ | 24 | 2500 | 346.0 | 346.0 | 33.0 |
| CY74FCT652CTSOCT | SOIC | DW | 24 | 2000 | 346.0 | 346.0 | 41.0 |
| CY74FCT652TQCT | SSOP/QSOP | DBQ | 24 | 2500 | 346.0 | 346.0 | 33.0 |

DW (R-PDSO-G24)

PLASTIC SMALL-OUTLINE PACKAGE

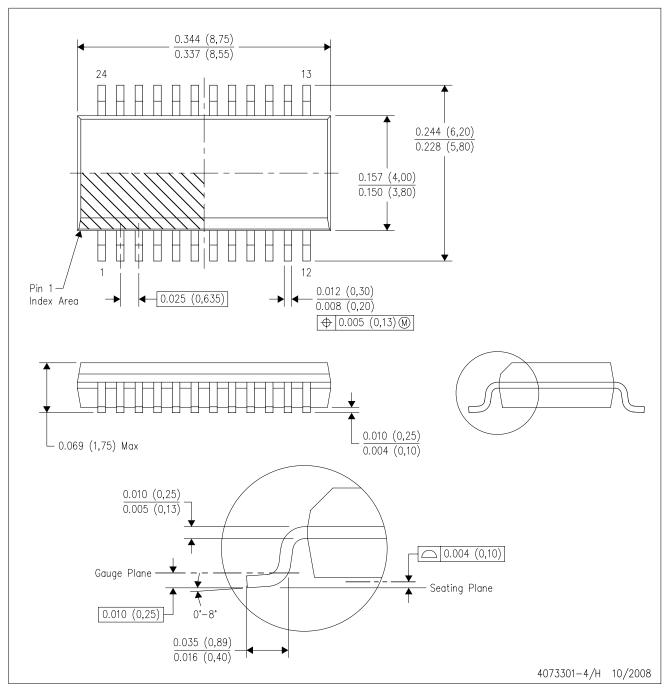


NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AD.

DBQ (R-PDSO-G24)

PLASTIC SMALL-OUTLINE PACKAGE



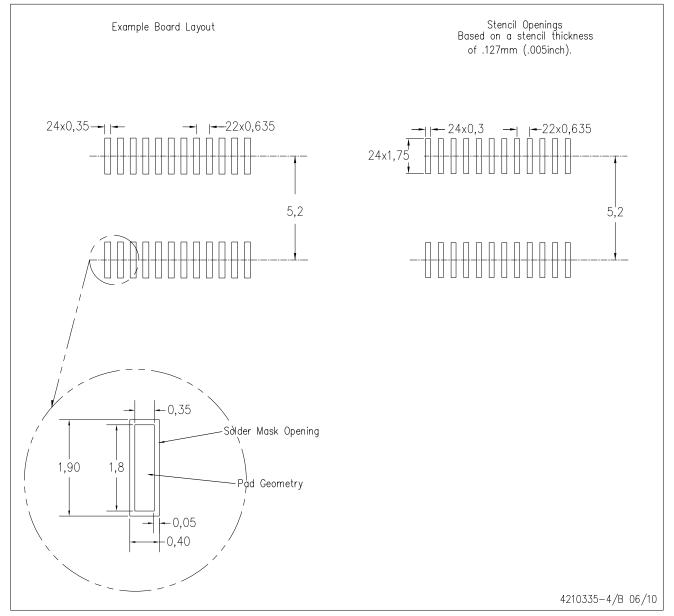
NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15) per side.
- D. Falls within JEDEC MO-137 variation AE.



DBQ (R-PDSO-G24)

PLASTIC SMALL OUTLINE PACKAGE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.

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